

L Number	Hits	Search Text	DB	Time stamp
1	41	plane and ((stack or stacking) with fault with density)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 14:02
2	31	plane with deviation with ("(111)" or "111")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 14:29
3	32	(plane with deviation) and (solar adj cell)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 14:34
4	37	"111" with plane with deviation	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 14:35
-	26137	solar adj cell	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/04 18:17
-	1285	anodizing same porous	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/04 16:54
-	38	(solar adj cell) and (anodizing same porous)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/04 17:52
-	15	"111" and ((solar adj cell) and (anodizing same porous))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 11:47
-	7	("3648653"   "4032370"   "4160682"   "4243472"   "4778478"   "5544616"   "5922126").PN.	USPAT	2003/09/04 17:45
-	6	("4816420"   "5445991"   "5536361"   "5710057"   "5966620"   "6054363").PN.	USPAT	2003/09/04 17:47
-	23	((solar adj cell) and (anodizing same porous)) not ("111" and ((solar adj cell) and (anodizing same porous)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/04 17:52
-	6145	(silicon with (substrate or wafer)) same ("111" or "(111)")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 10:48
-	151	(solar adj cell) and ((silicon with (substrate or wafer)) same ("111" or "(111)"))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/04 18:20
-	46	(solar adj cell) same ((silicon with (substrate or wafer)) same ("111" or "(111)"))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/04 18:51

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-	26	liquid with epitaxial with silicon with porous	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/04 18:52
-	9	(liquid with epitaxial with silicon with porous) and ("111" or "(111)")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/04 18:52
-	7	("3893869"   "4927781"   "5331180"   "5372962"   "5427977"   "5510633"   "5626159").PN.	USPAT	2003/09/04 19:05
-	21	deviation same (silicon with (substrate or wafer)) same ("111" or "(111)")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 10:49
-	2	((("5,100,478") or ("6,426,274B1"))).PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 11:49
-	4	((("5,100,478") or ("6,426,274"))).PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 13:51